

<b>Notice of References Cited</b>	Application/Control No. 10/792,257		Applicant(s)/Patent Under Reexamination STEYSKAL ET AL.	
	Examiner Nguyen T Ha		Art Unit 2831	Page 1 of 1

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*	C	US-6,594,136	07-2003	Kuroda et al.	361/306.1
*	D	US-6,549,395	04-2003	Naito et al.	361/306.1
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	M	US-			

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**NON-PATENT DOCUMENTS**

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